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# FDS6911

# Dual N-Channel Logic Level PowerTrench<sup>®</sup> MOSFET 20V, 7.5A, $13m\Omega$

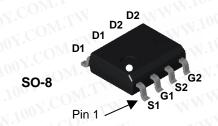
# **General Description**

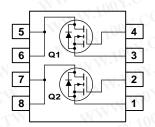
These N-Channel Logic Level MOSFETs are produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.

# **Features**

- $r_{DS(on)} = 13 \text{ m}\Omega$  @ V<sub>GS</sub> = 10 V  $r_{DS(on)} = 17 \text{ m}\Omega$  @ V<sub>GS</sub> = 4.5 V
- Fast switching speed
- Low gate charge
- High performance trench technology for extremely low R<sub>DS(ON)</sub>
- High power and current handling capability





# Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter	1001	Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage	M. OON	20	V
V <sub>GSS</sub>	Gate-Source Voltage	MAITON	± 20	V
I <sub>D</sub>	Drain Current - Continuous	(Note 1a)	7.5	Α
	- Pulsed	1100	20	1007.
P <sub>D</sub>	Power Dissipation for Single Operation	(Note 1a)	1.6	W
	WW.100 COM.	(Note 1b)	1.0 I	M. D.
	N VI 100Y.	(Note 1c)	0.9	7 W.10
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperat	ure Range	-55 to +150	°C

# **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	78	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	40	°C/W

**Package Marking and Ordering Information** 

Device Marking	Device	Reel Size	Tape width	Quantity
FDS6911	FDS6911	13"	12mm	2500 units

MITW OM.TW

LCOM.TW

ov.COM.TW 00Y.COM.TW

100Y.COM.TW

WWW.10 Y.COM.TW

WWW.100Y

WWW.100

WWW.1

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Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics	WW.1007.CO	VIIA	_ 1		
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_{D} = 250 \mu\text{A}$	20			V
ΔBV <sub>DSS</sub> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A$ , Referenced to $25^{\circ}C$	OM.	28		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 20 \text{ V},  V_{GS} = 0 \text{ V}$ $V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55^{\circ}\text{C}$	MO	IN	1 10	μА
I <sub>GSS</sub>	Gate-Source Leakage	$V_{GS} = \pm 20 \text{ V},  V_{DS} = 0 \text{ V}$	401		±100	nA
On Char	acteristics (Note 2)					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$	1	1.8	3	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	$I_D = 250 \mu A$ , Referenced to $25^{\circ}C$	OY.C	-4.7	LM	mV/°C
r <sub>DS(on)</sub>	Static Drain–Source On–Resistance	$V_{GS} = 10 \text{ V},  I_D = 7.5 \text{ A}$ $V_{GS} = 4.5 \text{ V},  I_D = 6.5 \text{ A}$ $V_{GS} = 10 \text{ V},  I_D = 7.5 \text{ A}, T_J = 125 ^{\circ}\text{C}$	001.	10.6 13 14.5	13 17 20	mΩ
I <sub>D(on)</sub>	On-State Drain Current	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 5 V	20	J.CO	117.	Λ A
<b>g</b> FS	Forward Transconductance	$V_{DS} = 5 \text{ V}, \qquad I_{D} = 7.5 \text{ A}$	1.700	36	Mi	S
Dynamic	Characteristics	Y.COM.TW WY	W.10	$0\lambda$ .	OM	. A.
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 15 \text{ V},  V_{GS} = 0 \text{ V},$	-x11	1130	Mo	pF
Coss	Output Capacitance	f = 1.0 MHz	/ A	300		pF
C <sub>rss</sub>	Reverse Transfer Capacitance	COM	WW	100	$^{1}CO_{D}$	pF
$R_G$	Gate Resistance	$V_{GS} = 15 \text{ mV}, f = 1.0 \text{ MHz}$	V	2.4	-1 CO	Ω
Switchin	g Characteristics (Note 2)	100Y.COM.TW	Mari	W.100	JY.	T.Mo
$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 15 \text{ V},  I_D = 1 \text{ A},$	MA	9	18	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS} = 10 \text{ V},  R_{GEN} = 6 \Omega$	W	5	10	ns
$t_{d(off)}$	Turn-Off Delay Time	M.100 COM.	- 1	26	42	ns
t <sub>f</sub>	Turn-Off Fall Time	WITOOX.	44	7	14	ns
$Q_{g(TOT)}$	Total Gate Charge at Vgs=10V	TIOOT.CO TITY		17	24	nC
$Q_g$	Total Gate Charge at Vgs=5V	$V_{DD} = 15 \text{ V},  I_D = 7.5 \text{ A},$		9	13	nC
$Q_{gs}$	Gate-Source Charge	M. Ing COM.		3.1	M.r.	nC
$Q_{gd}$	Gate-Drain Charge	11. W. 1001. COM.I.A.		2.7	1. W.	nC

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Electrical Characteristics TA = 25°C unless otherwise noted						
Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-So	ource Diode Characteristics a	nd Maximum Ratings	TW	•		
Is	Maximum Continuous Drain-Source	e Diode Forward Current	TW		1.3	Α
$V_{SD}$	Drain–Source Diode Forward Voltage	$V_{GS} = 0 \text{ V},  I_S = 1.3 \text{ A}  \text{(Note 2)}$	M.TV	-7	1.2	V
t <sub>rr</sub>	Diode Reverse Recovery Time	$I_F = 7.5 \text{ A},  d_{iF}/d_t = 100 \text{ A/}\mu\text{s}$	Tim	24		nS
Q <sub>rr</sub>	Diode Reverse Recovery Charge	N WWW.IOV.C	O St.	13		nC

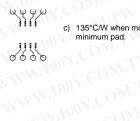
1. R<sub>0JA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta CA}$  is determined by the user's board design.



a) 78°C/W when mounted on a 0.5 in<sup>2</sup> pad of 2 oz



b) 125°C/W when mounted on a .02 in<sup>2</sup> pad of 2 oz copper



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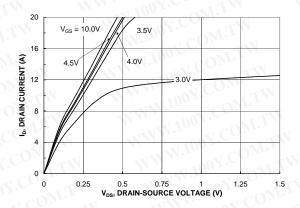
c) 135°C/W when mounted on a minimum pad.

Scale 1:1 on letter size paper

WWW.100Y.COM.TW 2. Pulse Test: Pulse Width <  $300\mu s$ , Duty Cycle < 2.0%

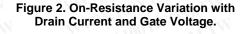
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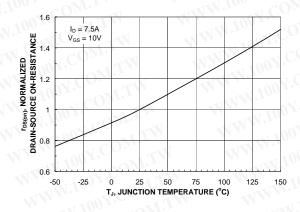
# **Typical Characteristics**



0.6 0 4 8 12 16 20

Figure 1. On-Region Characteristics.





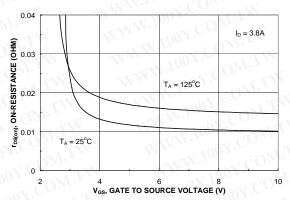
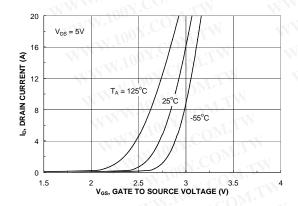


Figure 3. On-Resistance Variation with Temperature.

Figure 4. On-Resistance Variation with Gate-to-Source Voltage.



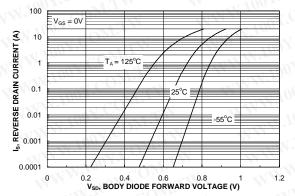


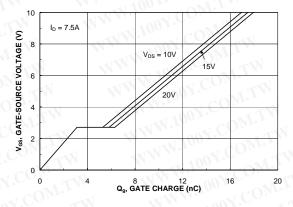
Figure 5. Transfer Characteristics.

Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

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f = 1MHz

# **Typical Characteristics**



 $C_{rss}$ 10 15 20 V<sub>DS</sub>, DRAIN TO SOURCE VOLTAGE (V)

 $C_{\text{oss}}$ 

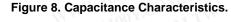
1200 <u>급</u> 1000

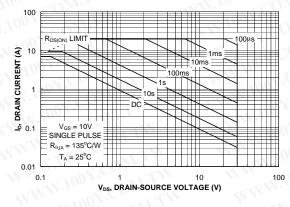
400

200

CAPACITANCE 800 600

Figure 7. Gate Charge Characteristics.





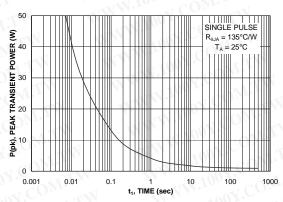


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

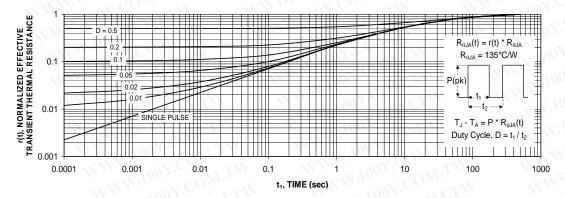


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

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